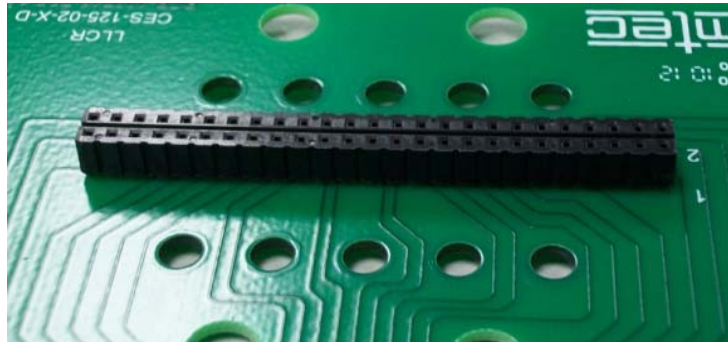




Project Number: Design Qualification Test Report		Tracking Code: 187546_Report_Rev_1	
Requested by: Mark Shireman		Date: 11/4/2016	Product Rev: N/A
Part #: CES-125-02-L-D/TSW-125-07-L-D CES-125-02-S-D/TSW-125-07-S-D		Lot #: N/A	Tech: Troy Cook Eng: Eric Mings
Part description: CES/TSW			Qty to test: 16
Test Start: 03/09/2012		Test Completed: 04/02/2012	



## DESIGN QUALIFICATION TEST REPORT

**CES/TSW**

**CES-125-02-L-D/TSW-125-07-L-D (10u" Gold)**

**CES-125-02-S-D/TSW-125-07-S-D (30u" Gold)**

Tracking Code: 187546_Report_Rev_1	Part #: CES-125-02-L-D\TSW-125-07-L-D CES-125-02-S-D\TSW-125-07-S-D
Part description: CES\TSW	

## CERTIFICATION

All instruments and measuring equipment were calibrated to National Institute for Standards and Technology (NIST) traceable standards according to ISO 10012-1 and ANSI/NCSL 2540-1, as applicable.

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### SCOPE

To perform the following tests: Design Qualification test. Please see test plan.

### APPLICABLE DOCUMENTS

Standards: EIA Publication 364

### TEST SAMPLES AND PREPARATION

- 1) All materials were manufactured in accordance with the applicable product specification.
- 2) All test samples were identified and encoded to maintain traceability throughout the test sequences.
- 3) After soldering, the parts to be used for LLCR testing were cleaned according to TLWI-0001.
- 4) Either an automated cleaning procedure or an ultrasonic cleaning procedure may be used.
- 5) The automated procedure is used with aqueous compatible soldering materials.
- 6) Parts not intended for testing LLCR are visually inspected and cleaned if necessary.
- 7) Any additional preparation will be noted in the individual test sequences.
- 8) Solder Information: Lead Free
- 9) Samtec Test PCBs used:

**FLOWCHARTS****LLCR/Durability**

TEST STEP	GROUP A1 10u" Gold (-L) 8 Mated Sets	GROUP B1 30u" Gold (-S) 8 Mated Sets
01	LLCR-1	LLCR-1
02	100 Cycles	100 Cycles
03	LLCR-2	LLCR-2
04	Thermal Shock (Mated and Undisturbed)	Thermal Shock (Mated and Undisturbed)
05	LLCR-3	LLCR-3
06	Cyclic Humidity (Mated and Undisturbed)	Cyclic Humidity (Mated and Undisturbed)
07	LLCR-4	LLCR-4

Thermal Shock = EIA-364-32, Table II, Test Condition I:

-55°C to +85°C 1/2 hour dwell, 100 cycles

Humidity = EIA-364-31, Test Condition B (240 Hours)

and Method III (+25°C to +65°C @ 90% RH to 98% RH)

ambient pre-condition and delete steps 7a and 7b

LLCR = EIA-364-23, LLCR

20 mV Max, 100 mA Max

Use Keithley 580 or 3706 in 4 wire dry circuit mode

**ATTRIBUTE DEFINITIONS**

The following is a brief, simplified description of attributes.

**THERMAL SHOCK:**

- 1) EIA-364-32, *Thermal Shock (Temperature Cycling) Test Procedure for Electrical Connectors*.
- 2) Test Condition 1: -55°C to +85°C
- 3) Test Time: ½ hour dwell at each temperature extreme
- 4) Number of Cycles: 100
- 5) All test samples are pre-conditioned at ambient.
- 6) All test samples are exposed to environmental stressing in the mated condition.

**HUMIDITY:**

- 1) Reference document: EIA-364-31, *Humidity Test Procedure for Electrical Connectors*.
- 2) Test Condition B, 240 Hours.
- 3) Method III, +25° C to + 65° C, 90% to 98% Relative Humidity excluding sub-cycles 7a and 7b.
- 4) All samples are pre-conditioned at ambient.
- 5) All test samples are exposed to environmental stressing in the mated condition.

**LLCR:**

- 1) EIA-364-23, *Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets*.
- 2) A computer program, *LLCR 221.exe*, ensures repeatability for data acquisition.
- 3) The following guidelines are used to categorize the changes in LLCR as a result from stressing
  - a. <= +5.0 mOhms: ----- Stable
  - b. +5.1 to +10.0 mOhms: ----- Minor
  - c. +10.1 to +15.0 mOhms: ----- Acceptable
  - d. +15.1 to +50.0 mOhms: ----- Marginal
  - e. +50.1 to +2000 mOhms: ----- Unstable
  - f. >+2000 mOhms: ----- Open Failure

**RESULTS****LLCR Durability****CES-125-02-L-D/TSW-125-07-L-D (10u" Gold)****192 LLCR test points**

- **Initial** -----4.34 mOhms Max
- **Durability 100 cycles**
  - <= +5.0 mOhms ----- 192 Points ----- Stable
  - +5.1 to +10.0 mOhms -----0 Points ----- Minor
  - +10.1 to +15.0 mOhms -----0 Points ----- Acceptable
  - +15.1 to +50.0 mOhms -----0 Points ----- Marginal
  - +50.1 to +2000 mOhms-----0 Points ----- Unstable
  - >+2000 mOhms -----0 Points ----- Open Failure
- **Thermal**
  - <= +5.0 mOhms ----- 192 Points ----- Stable
  - +5.1 to +10.0 mOhms -----0 Points ----- Minor
  - +10.1 to +15.0 mOhms -----0 Points ----- Acceptable
  - +15.1 to +50.0 mOhms -----0 Points ----- Marginal
  - +50.1 to +2000 mOhms-----0 Points ----- Unstable
  - >+2000 mOhms -----0 Points ----- Open Failure
- **Humidity**
  - <= +5.0 mOhms ----- 192 Points ----- Stable
  - +5.1 to +10.0 mOhms -----0 Points ----- Minor
  - +10.1 to +15.0 mOhms -----0 Points ----- Acceptable
  - +15.1 to +50.0 mOhms -----0 Points ----- Marginal
  - +50.1 to +2000 mOhms-----0 Points ----- Unstable
  - >+2000 mOhms -----0 Points ----- Open Failure

**CES-125-02-S-D/TSW-125-07-S-D (30u" Gold)****192 LLCR test points**

- **Initial** -----5.00 mOhms Max
- **Durability 100 cycles**
  - <= +5.0 mOhms ----- 192 Points ----- Stable
  - +5.1 to +10.0 mOhms -----0 Points ----- Minor
  - +10.1 to +15.0 mOhms -----0 Points ----- Acceptable
  - +15.1 to +50.0 mOhms -----0 Points ----- Marginal
  - +50.1 to +2000 mOhms-----0 Points ----- Unstable
  - >+2000 mOhms -----0 Points ----- Open Failure
- **Thermal**
  - <= +5.0 mOhms ----- 192 Points ----- Stable
  - +5.1 to +10.0 mOhms -----0 Points ----- Minor
  - +10.1 to +15.0 mOhms -----0 Points ----- Acceptable
  - +15.1 to +50.0 mOhms -----0 Points ----- Marginal
  - +50.1 to +2000 mOhms-----0 Points ----- Unstable
  - >+2000 mOhms -----0 Points ----- Open Failure
- **Humidity**
  - <= +5.0 mOhms ----- 192 Points ----- Stable
  - +5.1 to +10.0 mOhms -----0 Points ----- Minor
  - +10.1 to +15.0 mOhms -----0 Points ----- Acceptable
  - +15.1 to +50.0 mOhms -----0 Points ----- Marginal
  - +50.1 to +2000 mOhms-----0 Points ----- Unstable
  - >+2000 mOhms -----0 Points ----- Open Failure

**DATA SUMMARIES****LLCR Durability: CES-125-02-L-D/TSW-125-07-L-D (10u" Gold)**

- 1) A total of 192 points were measured.
- 2) EIA-364-23, *Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets*.
- 3) A computer program, *LLCR 221.exe*, ensures repeatability for data acquisition.
- 4) The following guidelines are used to categorize the changes in LLCR as a result from stressing.
  - a.  $\leq +5.0$  mOhms:----- Stable
  - b.  $+5.1$  to  $+10.0$  mOhms:----- Minor
  - c.  $+10.1$  to  $+15.0$  mOhms:----- Acceptable
  - d.  $+15.1$  to  $+50.0$  mOhms:----- Marginal
  - e.  $+50.1$  to  $+2000$  mOhms:----- Unstable
  - f.  $>+2000$  mOhms:----- Open Failure

<b>LLCR Measurement Summaries by Pin Type</b>				
Date	3/9/2012	3/9/2012	3/20/2012	4/2/2012
Room Temp (Deg C)	22	22	22	21
Rel Humidity (%)	27	35	36	44
Technician	Troy Cook	Troy Cook	Troy Cook	Troy Cook
mOhm values	<b>Actual Initial</b>	<b>Delta 100 Cycles</b>	<b>Delta Thermal</b>	<b>Delta Humidity</b>
<b>Pin Type 1: Signal</b>				
Average	3.77	0.12	0.14	0.14
St. Dev.	0.16	0.10	0.18	0.17
Min	3.42	0.00	0.00	0.00
Max	4.34	0.72	1.39	1.22
Summary Count	192	192	192	192
Total Count	192	192	192	192

<b>LLCR Delta Count by Category</b>						
	<b>Stable</b>	<b>Minor</b>	<b>Acceptable</b>	<b>Marginal</b>	<b>Unstable</b>	<b>Open</b>
mOhms	$\leq 5$	$>5 \text{ \& } \leq 10$	$>10 \text{ \& } \leq 15$	$>15 \text{ \& } \leq 50$	$>50 \text{ \& } \leq 1000$	$>1000$
<b>100 Cycles</b>	192	0	0	0	0	0
<b>Thermal</b>	192	0	0	0	0	0
<b>Humidity</b>	192	0	0	0	0	0

**DATA SUMMARIES Continued****LLCR Durability: CES-125-02-S-D/TSW-125-07-S-D (30u" Gold)**

- 1) A total of 192 points were measured.
- 2) EIA-364-23, *Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets*.
- 3) A computer program, *LLCR 221.exe*, ensures repeatability for data acquisition.
- 4) The following guidelines are used to categorize the changes in LLCR as a result from stressing.
  - a.  $\leq +5.0$  mOhms: ----- Stable
  - b.  $+5.1$  to  $+10.0$  mOhms: ----- Minor
  - c.  $+10.1$  to  $+15.0$  mOhms: ----- Acceptable
  - d.  $+15.1$  to  $+50.0$  mOhms: ----- Marginal
  - e.  $+50.1$  to  $+2000$  mOhms: ----- Unstable
  - f.  $>+2000$  mOhms: ----- Open Failure

<b>LLCR Measurement Summaries by Pin Type</b>				
Date	3/9/2012	3/9/2012	3/20/2012	4/2/2012
Room Temp (Deg C)	22	22	22	21
Rel Humidity (%)	27	30	36	43
Technician	Troy Cook	Troy Cook	Troy Cook	Troy Cook
mOhm values	<b>Actual Initial</b>	<b>Delta 100 Cycles</b>	<b>Delta Thermal</b>	<b>Delta Humidity</b>
<b>Pin Type 1: Signal</b>				
Average	3.98	0.14	0.15	0.18
St. Dev.	0.30	0.14	0.17	0.18
Min	3.35	0.00	0.00	0.00
Max	5.00	0.94	1.64	1.85
Summary Count	192	192	192	192
Total Count	192	192	192	192

<b>LLCR Delta Count by Category</b>						
	<b>Stable</b>	<b>Minor</b>	<b>Acceptable</b>	<b>Marginal</b>	<b>Unstable</b>	<b>Open</b>
mOhms	$\leq 5$	$>5 \text{ \& } \leq 10$	$>10 \text{ \& } \leq 15$	$>15 \text{ \& } \leq 50$	$>50 \text{ \& } \leq 1000$	$>1000$
<b>100 Cycles</b>	192	0	0	0	0	0
<b>Thermal</b>	192	0	0	0	0	0
<b>Humidity</b>	192	0	0	0	0	0

Tracking Code: 187546_Report_Rev_1	Part #: CES-125-02-L-D\TSW-125-07-L-D CES-125-02-S-D\TSW-125-07-S-D
Part description: CES\TSW	

## EQUIPMENT AND CALIBRATION SCHEDULES

**Equipment #:** MO-04

**Description:** Multimeter /Data Acquisition System

**Manufacturer:** Keithley

**Model:** 2700

**Serial #:** 0798688

**Accuracy:** See Manual

... Last Cal: 04/30/2011, Next Cal: 04/30/2012

**Equipment #:** THC-02

**Description:** Temperature/Humidity Chamber

**Manufacturer:** Thermotron

**Model:** SE-1000-6-6

**Serial #:** 31808

**Accuracy:** See Manual

... Last Cal: 02/16/2012, Next Cal: 02/16/2013

**Equipment #:** TSC-01

**Description:** Vertical Thermal Shock Chamber

**Manufacturer:** Cincinnatti Sub Zero

**Model:** VTS-3-6-6-SC/AC

**Serial #:** 10-VT14993

**Accuracy:** See Manual

... Last Cal: 05/18/2011, Next Cal: 05/18/2012